Diagnosys has a policy of continuous product improvement and reserves the right to change technical specifications at any time without prior notice. Diagnosys does not accept liability for errors or misprints in this document.

Data Capture Pod (DCP)
As an optional accessory the powerful DCP helps you develop functional test programs for devices that are not included in the extensive TestVue component library. The DCP captures live data, while a device is active in the circuit. Powerful tools in the TestVue software convert the captured data into a functional device program that can be stored for immediate or future use.

Test Program Services
Diagnosys offers test program writing services to help you smooth peaks in demand or to provide a complete turnkey solution ready for use. Supported by a worldwide team of experienced engineers test programs are developed, proven and installed to ensure a ready-to-use solution for you.

Return on Investment:
The PinPoint system is in use with major military and commercial customers worldwide and has demonstrated excellent returns on investment. This brochure will give you an overview of some key features but our sales team will be happy to discuss the PinPoint in more detail and explores how it can help you.

For your local office details please visit our web site: www.diagnosys.com

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Multi-strategy testing for confidence...

Test of Individual Components and Edge connectors testing [1]
The PinPoint system performs tests on individual components using in-circuit testing methods and a standardized test technique. These dynamic digital and analog nanos can precisely correct any errors of each device and can also detect opens, shorts, voltage, digital failures and incorrect, broken or missing components on networks. These test can also be applied at the edge connector of a circuit to prove the functionality of the whole circuit.

Control PXI and GPIB instrumentation [5]
Extending the capability of the PinPoint system even further is its inherent capability to control PXI and GPIB instruments. Having PXI control of the instruments through the user friendly TestFlow™ software allows you to create functional testing tests for your circuits. Instrument Strategizer gives the graphic capability to program and sequence instruments with either tools to provide a seamless mixed-significant program. Additional power supplies can also be added to enhance the standard test supply and power test supplies for embedded test capabilities.

Powerful V/I testing [2]
In addition to the advanced and powerful digitalizations, the PinPoint system also adds a V/I testing technique. This technique applies a sinusoidal signal to a network and learns the four quadrant signature for it. This signature is then stored and used for compensation of the network or other boards giving an instant indication of any error. The results are graphically displayed on the screen. This power of technique can be applied to any board and is therefore useful when little or no information is available about the device or network being tested.

Parametric Test Unit (PTU) [3]
Four channel parametric on the PinPoint's VLSI Test card is dedicated to analog and current sources. These channels can be used for functional testing of electronic components both in and out of circuit, for example, fig. of transistor or semiconductor junction forward voltage.

LCR Bridge [4]
The LCR Bridge is used to measure the values of Inductors, Capacitors and Resistors in out of circuit. Provided by TestFlow™ software you immediately test in circuit of the single forward test and can run it in immediately testing components. Measuring the values of a network impedance is now a straight forward test that enhances the diagnostic capabilities available in the PinPoint system.

Powerful Software Features...

TestFlow™ automatically generates a test program, for a board under test, as the components are led out by the operator. This allows test programs to be created in hours rather than weeks. The test program is quick and simple. It also gives the programmer the ability to add conditional branches, subroutines, operator test instruction and limits checks on the circuit as a whole.

SeaWave™ enables detailed analysis of logic inputs and outputs to the DUT. This is extremely useful for fault finding and debugging programs. Detailed component information is available from the PinPoint component library. The library, which is being added all the time, currently contains over 6000 component test programs including memory, microcontroller, and bipolar components. Many of the components in the library also have data sheets included that can provide valuable information when writing board programs. All these powerful software features are available in an intuitive Windows-based environment including DLL and Windows API' that any program can be executed from the TestVue™ software platform, used on PinPoint II, offers a powerful array of features including Testflow™- Analog virtual instruments, SeaWave and a simple intuitive user interface.

Comprehensive testing to reduce No Fault Finds (NFF)...